MOSFET - Power, Single N-Channel, SO-8 FL 30 V, 3.4 m Ω , 71 A

NVMFS4C306N

Features

- Low R_{DS(on)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- AEC-Q101 Qualified and PPAP Capable
- NVMFS4C306NWF Wettable Flanks Option for Enhanced Optical Inspection
- These Devices are Pb-Free, Halogen Free/BFR Free and are RoHS Compliant

Applications

- Reverse Battery Protection
- DC-DC Converters Output Driver

MAXIMUM RATINGS (T_J = 25°C unless otherwise stated)

Parameter		Symbol	Value	Unit	
Drain-to-Source Voltage			V_{DSS}	30	V
Gate-to-Source Voltage			V_{GS}	±20	V
Continuous Drain		T _A = 25°C	I _D	20.6	Α
Current R _{θJA} (Notes 1, 2)		T _A = 100°C		14.5	
Power Dissipation R _{θJA} (Notes 1, 2)		T _A = 25°C	P _D	3	W
Continuous Drain Current R ₀ JC (Notes 1, 2, 3)	Steady State	T _C = 25°C	I _D	71	Α
Continuous Drain Current R _{0JC} (Notes 1, 2, 3)		T _C = 100°C		50	
Power Dissipation R _{θJC} (Notes 1, 2, 3)		T _C = 25°C	P _D	36.5	W
Pulsed Drain Current	$T_A = 25^{\circ}C, t_p = 10 \mu s$		I _{DM}	166	Α
Operating Junction and Storage Temperature Range			T _J , T _{STG}	-55 to +175	°C
Source Current (Body Diode)			I _S	28	Α
Single Pulse Drain-to-Source Avalanche Energy (T_J = 25°C, V_{GS} = 10 V, I_L = 37 A_{pk} , L = 0.1 mH, R_{GS} = 25 Ω) (Note 3)			E _{AS}	68	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

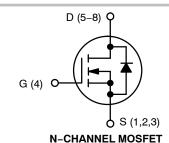
- 1. Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
- 2. Surface-mounted on FR4 board using the minimum recommended pad size.
- 3. Parts are 100% tested at $T_J = 25^{\circ}C$, $V_{GS} = 10$ V, $I_L = 27$ Apk, $E_{AS} = 36$ mJ.



ON Semiconductor®

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V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX
30 V	3.4 mΩ @ 10 V	71 A
30 V	4.8 mΩ @ 4.5 V	71 A





MARKING DIAGRAM D S S XXXXXXX S AYWZZ G D

4C06N = Specific Device Code for NVMFS4C306N

4C06WF= Specific Device Code of NVMFS4C306NWF

A = Assembly Location

Y = Year
W = Work Week
ZZ = Lot Traceability

ORDERING INFORMATION

Device	Package	Shipping [†]
NVMFS4C306NT1G	SO-8 FL (Pb-Free)	1500 / Tape & Reel
NVMFS4C306NWFT1G	SO-8 FL (Pb-Free)	1500 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	4.1	°C/W
Junction-to-Ambient - Steady State	$R_{ heta JA}$	49	C/VV

ELECTRICAL CHARACTERISTICS (T₁ = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS				•	•	•	•
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	V _{GS} = 0 V, I _D = 250 μA		30			V
Drain-to-Source Breakdown Voltage (transient)	V _{(BR)DSSt}	V _{GS} = 0 V, I _{D(aval)} = 12.6 A, T _{case} = 25°C, t _{transient} = 100 ns		34			٧
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /				14.4		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	$V_{GS} = 0 \text{ V}, T_{J} = 25^{\circ}\text{C}$				1.0	μΑ
		V _{DS} = 24 V T _J = 125°C			10		
Gate-to-Source Leakage Current	I _{GSS}	$V_{DS} = 0 V, V_{GS}$	_s = ±20 V			±100	nA
ON CHARACTERISTICS (Note 4)							
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D$	= 250 μΑ	1.3		2.1	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				3.8		mV/°
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 30 A		2.8	3.4	mΩ
		V _{GS} = 4.5 V	I _D = 30 A		4.0	4.8	
Forward Transconductance	9FS	V _{DS} = 1.5 V, I _D = 15 A			58		S
Gate Resistance	R_{G}	T _A = 25°C		0.3	1.0	2.0	Ω
CHARGES AND CAPACITANCES							
Input Capacitance	C _{ISS}				1683		
Output Capacitance	C _{OSS}	V _{GS} = 0 V, f = 1 MHz, V _{DS} = 15 V			841		pF
Reverse Transfer Capacitance	C _{RSS}				40		
Capacitance Ratio	C _{RSS} /C _{ISS}	V _{GS} = 0 V, V _{DS} = 15 V, f = 1 MHz			0.023		
Total Gate Charge	Q _{G(TOT)}				11.6		
Threshold Gate Charge	Q _{G(TH)}				2.6		1 .
Gate-to-Source Charge	Q_{GS}	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V}; I_D = 30 \text{ A}$			4.7		nC
Gate-to-Drain Charge	Q_{GD}				4.0		
Gate Plateau Voltage	V_{GP}				3.1		V
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 10 V, V _{DS} = 15 V; I _D = 30 A			26		nC
SWITCHING CHARACTERISTICS (Note 5)							
Turn-On Delay Time	t _{d(ON)}	V_{GS} = 4.5 V, V_{DS} = 15 V, I_{D} = 15 A, R_{G} = 3.0 Ω			10		
Rise Time	t _r				32		ns
Turn-Off Delay Time	t _{d(OFF)}				18		
Fall Time	t _f				5.0		
Turn-On Delay Time	t _{d(ON)}	V_{GS} = 10 V, V_{DS} = 15 V, I_{D} = 15 A, R_{G} = 3.0 Ω			8.0		- ns
Rise Time	t _r				28		
Turn-Off Delay Time	t _{d(OFF)}				24		
Fall Time	t _f				3.0		

- 4. Pulse Test: pulse width $\leq 300~\mu s$, duty cycle $\leq 2\%$. 5. Switching characteristics are independent of operating junction temperatures.

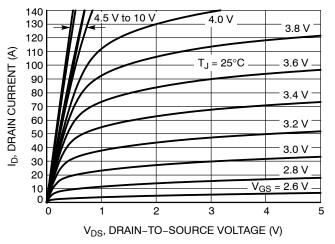
ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit		
DRAIN-SOURCE DIODE CHARACTERISTICS									
Forward Diode Voltage	V_{SD}	V _{GS} = 0 V, I _S = 10 A	T _J = 25°C		0.8	1.1	V		
			T _J = 125°C		0.63				
Reverse Recovery Time	t _{RR}	V_{GS} = 0 V, dIS/dt = 100 A/ μ s, I _S = 30 A			34				
Charge Time	ta				17		ns		
Discharge Time	t _b				17				
Reverse Recovery Charge	Q_{RR}				22		nC		

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

^{4.} Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%.
5. Switching characteristics are independent of operating junction temperatures.

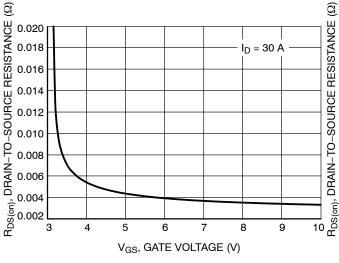
TYPICAL CHARACTERISTICS



80 70 $V_{DS} = 5 V$ ID, DRAIN CURRENT (A) 60 50 40 30 $T_J = 25^{\circ}C$ 20 $T_J = 125^{\circ}C$ 10 $T_J = -55^{\circ}C$ 0 0.5 1.0 1.5 2.5 3.0 3.5 2.0 V_{GS}, GATE-TO-SOURCE VOLTAGE (V)

Figure 1. On-Region Characteristics

Figure 2. Transfer Characteristics



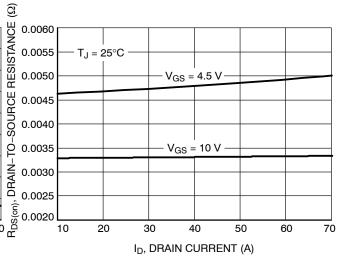
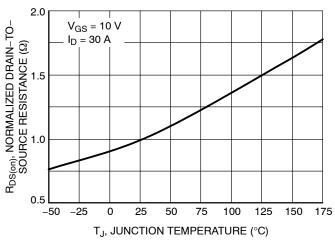


Figure 3. On-Resistance vs. Gate-to-Source Voltage

Figure 4. On-Resistance vs. Drain Current and Gate Voltage



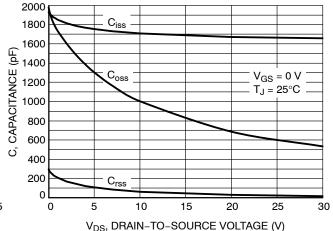


Figure 5. On–Resistance Variation with Temperature

Figure 6. Capacitance Variation

TYPICAL CHARACTERISTICS

1000

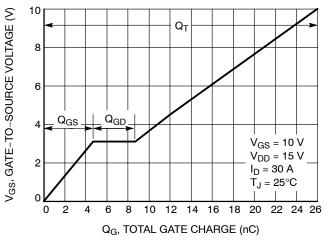


Figure 7. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

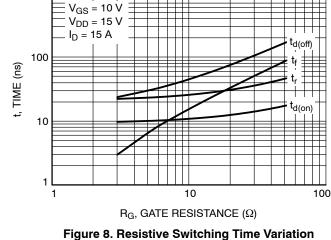


Figure 8. Resistive Switching Time Variation vs. Gate Resistance

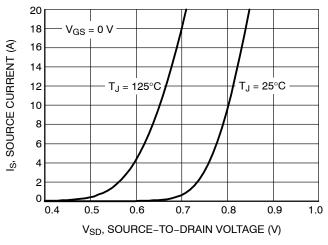


Figure 9. Diode Forward Voltage vs. Current

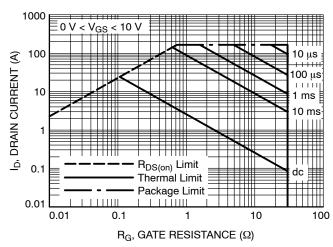


Figure 10. Maximum Rated Forward Biased Safe Operating Area

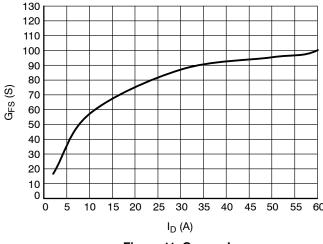


Figure 11. G_{FS} vs. I_D

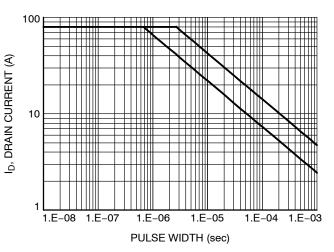


Figure 12. Avalanche Characteristics

TYPICAL CHARACTERISTICS

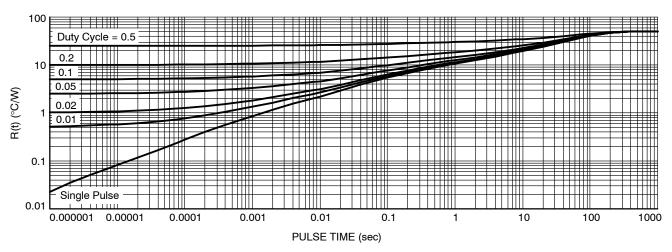
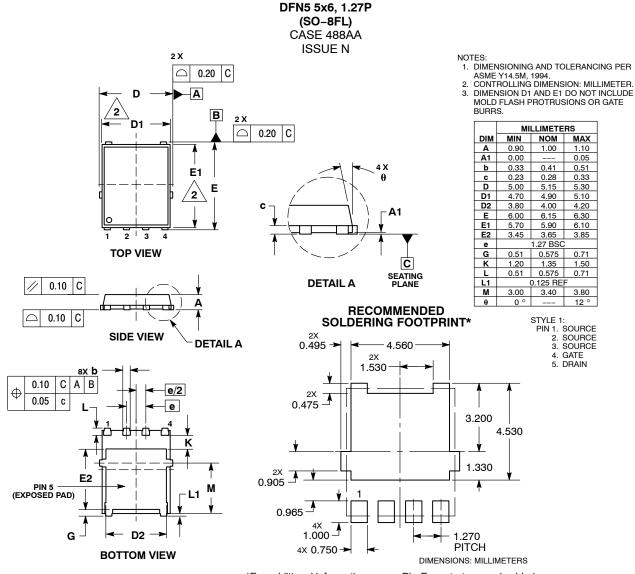


Figure 13. Thermal Response

PACKAGE DIMENSIONS



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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